

<b>Notice of References Cited</b>	Application/Control No. 10/803,777	Applicant(s)/Patent Under Reexamination ENDO ET AL.	
	Examiner Dah-Wei D. Yuan	Art Unit 1745	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,008,721	03-2006	Yamashita et al.	429/184
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO 02/058170	07-2002	WIPO	Yamashita et al.	H01M 2/06
	O					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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